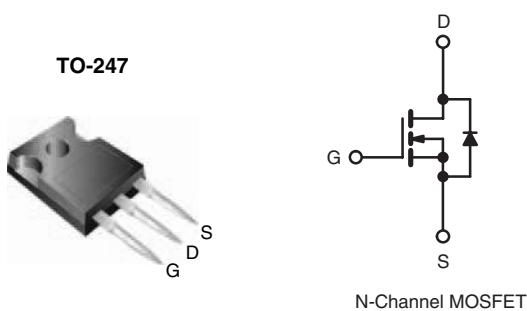


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	600
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.24
Q _g (Max.) (nC)	150
Q _{gs} (nC)	45
Q _{gd} (nC)	76
Configuration	Single



FEATURES

- Hard Switching Primary or PFS Switch
- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Enhanced Body Diode dV/dt Capability
- Lead (Pb)-free Available



BENEFITS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- Motor Drive

ORDERING INFORMATION

Package	TO-247
Lead (Pb)-free	IRFP22N60KPbF SiHFP22N60K-E3
SnPb	IRFP22N60K SiHFP22N60K

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	600	V
Gate-Source Voltage	V _{GS}	± 30	
Continuous Drain Current	I _D	22	A
		14	
Pulsed Drain Current ^a	I _{DM}	88	
Linear Derating Factor		2.9	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	380	mJ
Repetitive Avalanche Current ^a	I _{AR}	22	A
Repetitive Avalanche Energy ^a	E _{AR}	37	mJ
Maximum Power Dissipation	P _D	370	W
Peak Diode Recovery dV/dt ^c	dV/dt	15	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Starting T_J = 25 °C, L = 1.5 mH, R_G = 25 Ω, I_{AS} = 22 A (see fig. 12).
- I_{SD} ≤ 22 A, dI/dt ≤ 360 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.
- 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

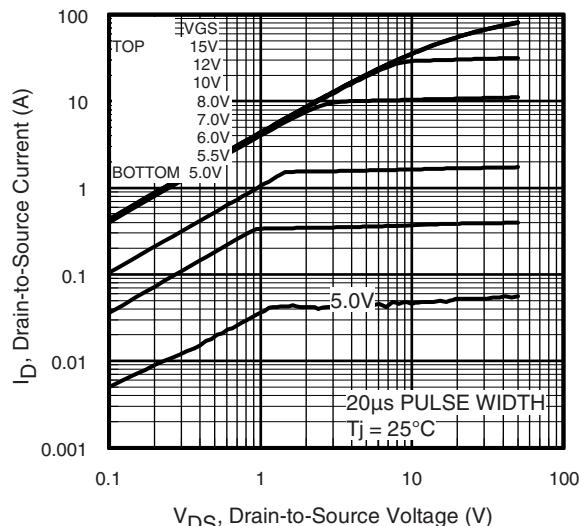
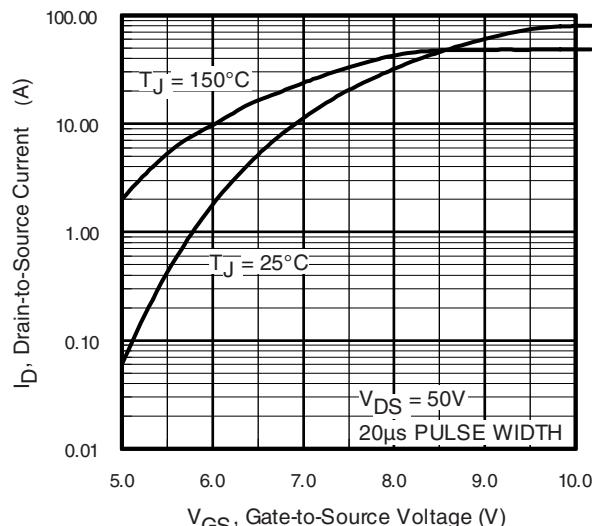
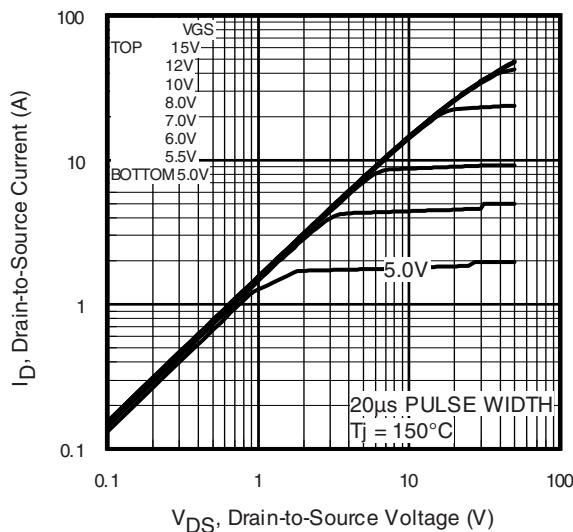
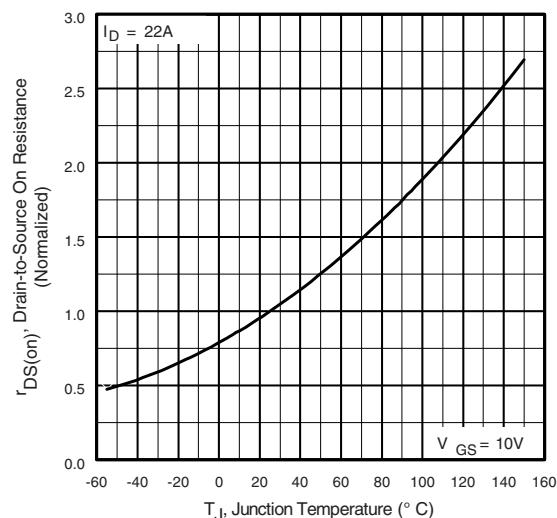
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	40	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.24	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.34	

SPECIFICATIONS $T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	600	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}^d$		-	0.30	-	$\text{V}/^{\circ}\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		3.0	-	5.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	50	μA	
		$V_{DS} = 480 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125 \text{ }^{\circ}\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 13 \text{ A}^b$	-	0.240	0.280	Ω	
Forward Transconductance	g_f	$V_{DS} = 50 \text{ V}$, $I_D = 13 \text{ A}^b$		11	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	3570	-	pF	
Output Capacitance	C_{oss}			-	350	-		
Reverse Transfer Capacitance	C_{rss}			-	36	-		
Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}$	$V_{DS} = 1.0 \text{ V}$, $f = 1.0 \text{ MHz}$	-	4710	-	nC	
			$V_{DS} = 480 \text{ V}$, $f = 1.0 \text{ MHz}$	-	92	-		
Effective Output Capacitance	$C_{oss eff.}$		$V_{DS} = 0 \text{ V}$ to 480 V	-	180	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 22 \text{ A}$, $V_{DS} = 480 \text{ V}$ see fig. 6 and 13 ^b	-	-	150	nC	
Gate-Source Charge	Q_{gs}			-	-	45		
Gate-Drain Charge	Q_{gd}			-	-	76		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 300 \text{ V}$, $I_D = 22 \text{ A}$, $R_G = 6.2$, $V_{GS} = 10 \text{ V}$, see fig. 10 ^b	$I_D = 22 \text{ A}$, $V_{DS} = 480 \text{ V}$ see fig. 6 and 13 ^b	-	26	-	ns	
Rise Time	t_r			-	99	-		
Turn-Off Delay Time	$t_{d(off)}$			-	48	-		
Fall Time	t_f			-	37	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	22	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	88		
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_S = 22 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.5	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}$	$I_F = 22 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$	-	590	890	ns	
		$T_J = 125 \text{ }^{\circ}\text{C}$		-	670	1010		
Body Diode Reverse Recovery Charge	Q_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}$		-	7.2	11	μC	
		$T_J = 125 \text{ }^{\circ}\text{C}$		-	8.5	13		
Reverse Recovery Current	I_{RRM}	$T_J = 25 \text{ }^{\circ}\text{C}$		-	26	39		
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.
- c. $C_{oss eff.}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS} .

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics

Fig. 4 - Normalized On-Resistance vs. Temperature

IRFP22N60K, SiHFP22N60K



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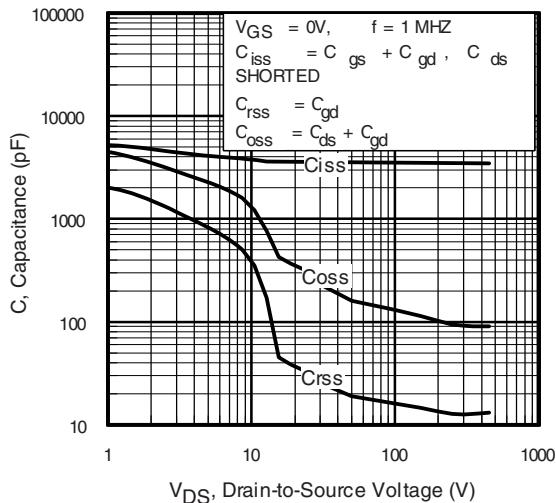


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

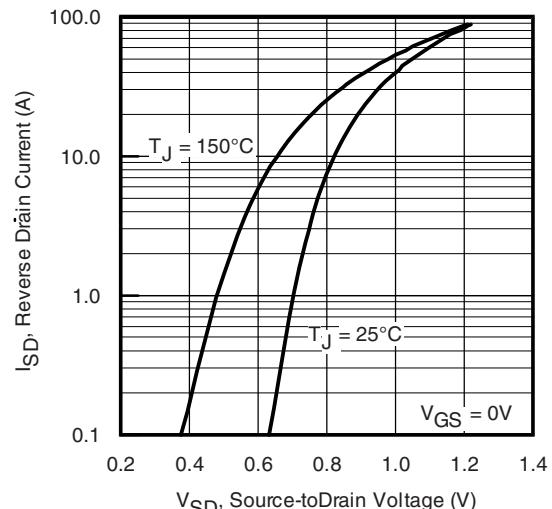


Fig. 7 - Typical Source-Drain Diode Forward Voltage

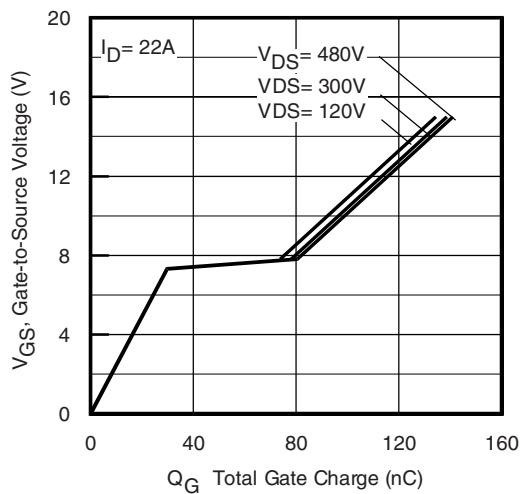


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

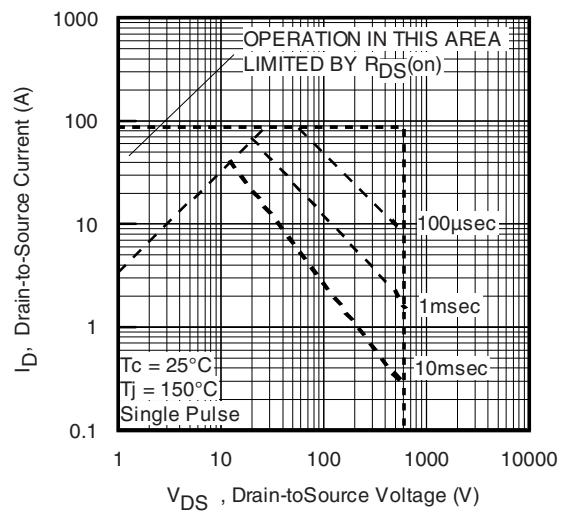
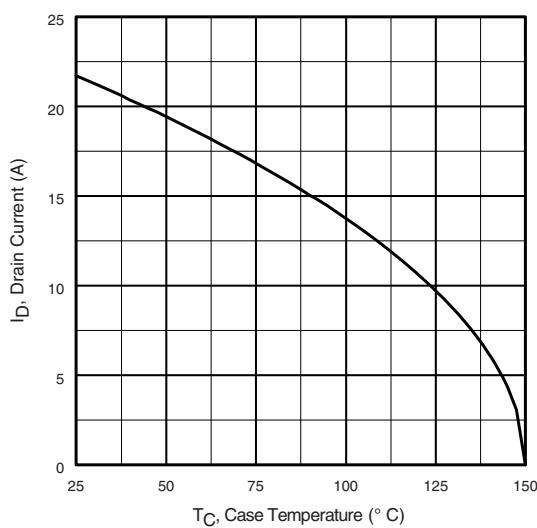
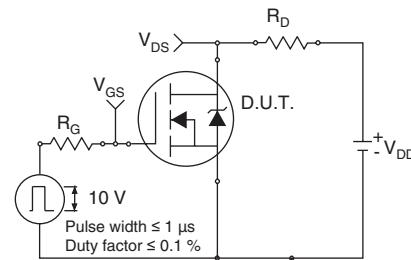
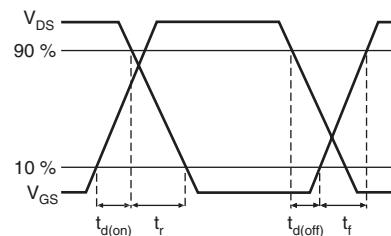
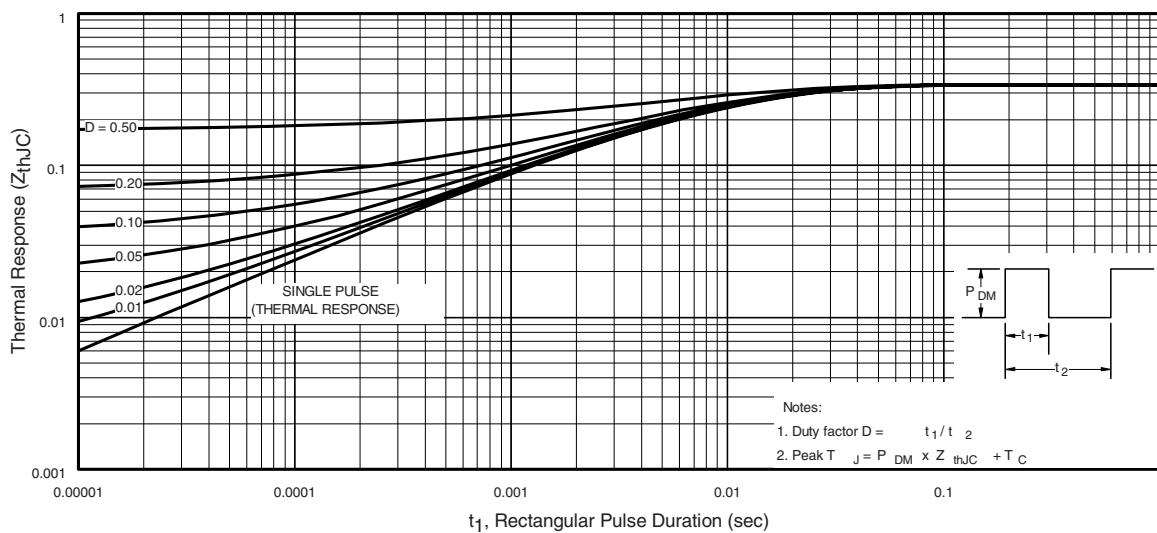
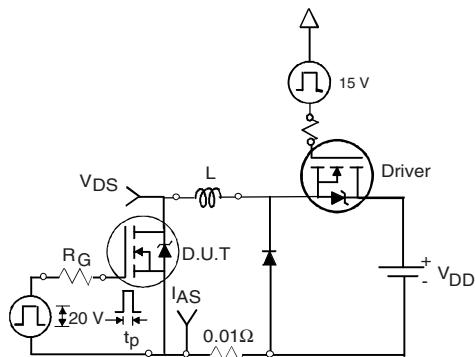
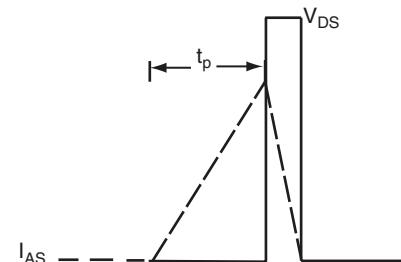


Fig. 8 - Maximum Safe Operating Area


Fig. 9 - Maximum Drain Current vs. Case Temperature

Fig. 10a - Switching Time Test Circuit

Fig. 10b - Switching Time Waveforms

Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

IRFP22N60K, SiHFP22N60K

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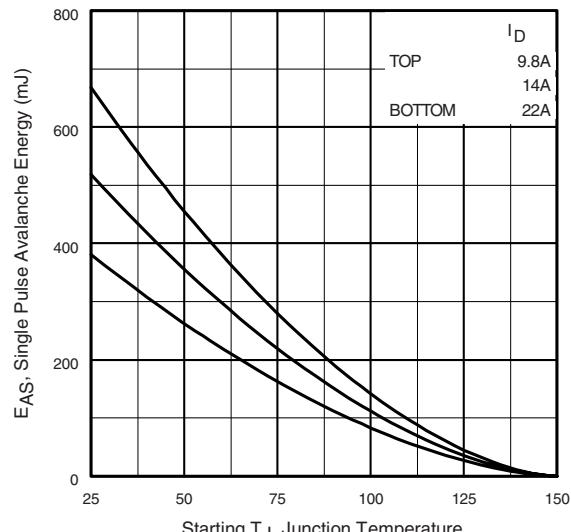


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

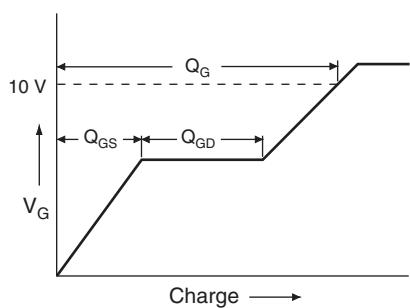


Fig. 13a - Basic Gate Charge Waveform

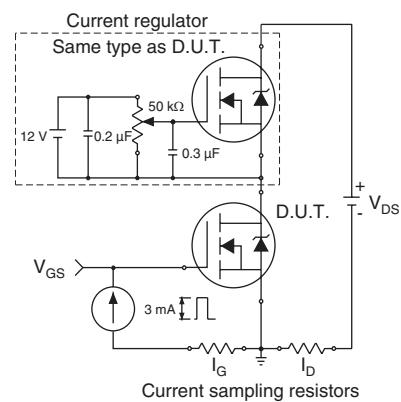
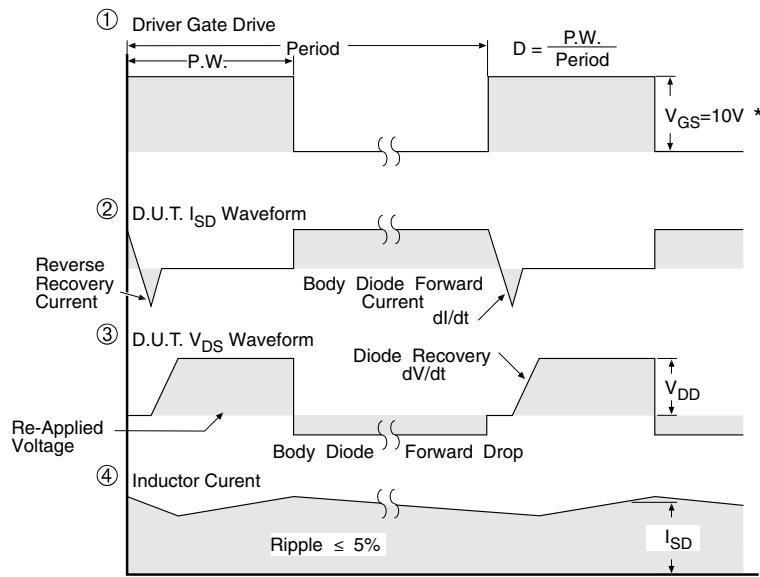
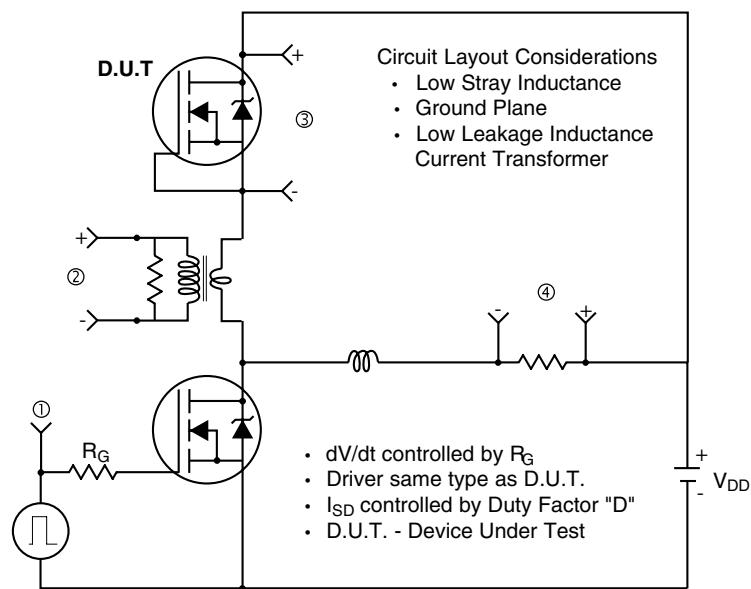


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5V$ for Logic Level Devices

Fig. 14 - For N-Channel

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